

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Saloma et al.
Serial No.: 10/520,729
Filed: January 7, 2005
For: METHOD FOR GENERATING HIGH-CONTRAST IMAGES
OF SEMICONDUCTOR SITES VIA ONE-PHOTON
OPTICAL BEAM-INDUCED CURRENT IMAGING AND
CONFOCAL REFLECTANCE MICROSCOPY
Art Unit: NOT YET ASSIGNED
Examiner: NOT YET ASSIGNED
Confirmation No.: 9716
Customer No.: 27623

Attorney Docket No.: 0002031USU/2280

Date: December 9, 2005

INFORMATION DISCLOSURE STATEMENT

**Mail Stop PCT
COMMISSIONER FOR PATENTS
P.O. Box 1450
Alexandria, VA 22313-1450
Attention: DO/EO/US**

Dear Sir:

In accordance with applicants' duty of disclosure under 37 C.F.R. §1.56, we are enclosing form PTO-1449 listing information that may be material to the patentability of this application.

37 C.F.R. 1.98 does not require a copy of U.S. patents or published U.S. patent applications to be included with an information disclosure statement. Accordingly,

Applicant is not including a copy of any U.S. patent or published U.S. patent application.

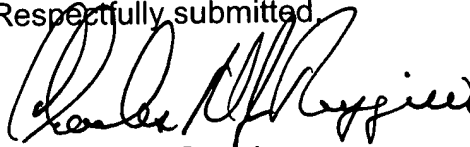
We are also enclosing copies of the non-US references listed on the attached PTO-1449.

It should be understood that attention has been called to the citations that have been deemed to be pertinent to the claimed present invention. In concluding what was pertinent, the criteria employed was considered most appropriate in light of the invention shown in the present application. However, the Examiner or others may deem some other criteria to be just as appropriate or more appropriate. Therefore, the Examiner is respectfully urged to review the listed citations and to make the usual careful independent search for other prior art that may be pertinent.

Since this Information Disclosure Statement is being filed prior to the issuance of the first Office Action based on the merits, no petition or fee is required.

Applicants respectfully request favorable consideration and that this application be passed to allowance.

Respectfully submitted,



Charles N.J. Ruggiero

Reg. No. 28,468

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Sheet 1 of 3

FORM PTO-1449

INFORMATION DISCLOSURE CITATION
IN AN APPLICATION

(Use several sheets if necessary)

Docket Number (Optional)

0002031USU/2280

Application Number

10/520,729

Applicant

Saloma et al.

Filing Date

January 5, 2005

Group Art Unit

NOT YET ASSIGNED

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5381224	1/10/95	Dixon et al.	356	72	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
	19733194	2/4/99	GERMANY (w/ Abstract)			XXX	
	2000088929	3/31/00	JAPAN (w/ Abstract)			XXX	

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)

	Notication of Transmittal of the International Search Report or The Declaration dated 26 March 2003 from PCT/PH02/00013
	Montangero et al. "A Som Approach to The Failure Physics of Optoelectronic Devices", Proceedings of the International Reliability Physics Symposium. Atlanta, March 23-25, 1993. New York, IEEE, US, Vol. SYMP. 31, March 23, 1993. Pp 380-385.
EXAMINER	DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP §609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

CUSTOMER NO.: 27623

Sheet 2 of 3

FORM PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)			Docket Number (Optional) 0002031USU/2280		Application Number 10/520,729	
			Applicant			
			Saloma et al.			
			Filing Date		Group Art Unit	
			January 5, 2005		NOT YET ASSIGNED	

U. S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)	
	Nikawa et al. "Failure Analysis Case Studies Using the IR-OBIRCH (Infared Optical beam Induced Resistance Change Method", Test Syposium Proceedings, Eighth Asian Shanghai, China November 16-18, 1999, Los Alamitos, CA, IEEE Comput. Soc, US November 16, 1999. pp 394-399 Ribes et al. "Reflected-light, photoluminescence and OBIC imaging Of solar cells using a confocal scanning laser MACROscope/microscope". Solar Energy Materials and Solar Cells 44, December 15, 1996. pp 439-350
EXAMINER	DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP §609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

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Sheet 3 of 3

FORM PTO-1449

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IN AN APPLICATION

(Use several sheets if necessary)

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FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)

Xu et al. "Comparision of one- and two-photon optical beam-induced current imaging". Journal of Applied Physics. Vol. 86 No. 4, August 15, 1999. pp 2226-2231.

EXAMINER

DATE CONSIDERED

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